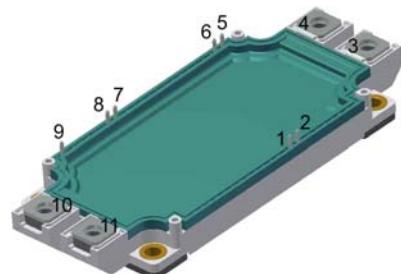


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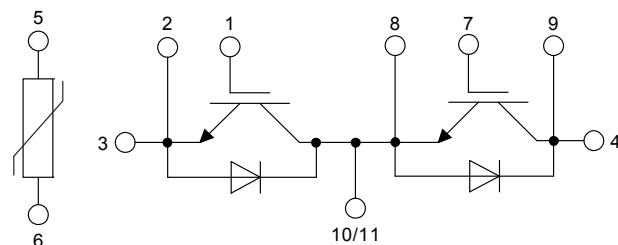
XPT IGBT Module

V_{CES} = 2x 1200 V
 I_{C25} = 465 A
 $V_{CE(sat)}$ = 1.8 V

Phase leg + free wheeling Diodes + NTC

Part number**MIXA300PF1200TSF**

Backside: isolated

**Features / Advantages:**

- High level of integration - only one power semiconductor module required for the whole drive
- Rugged XPT design (Xtreme light Punch Through) results in:
 - short circuit rated for 10 μ sec.
 - very low gate charge
 - low EMI
 - square RBSOA @ 3x I_C
- Thin wafer technology combined with the XPT design results in a competitive low $V_{CE(sat)}$
- Temperature sense included
- SONIC™ diode
 - fast and soft reverse recovery
 - low operating forward voltage

Applications:

- AC motor drives
- Pumps, Fans
- Air-conditioning system
- Inverter and power supplies
- UPS

Package: SimBus F

- Isolation Voltage: 3000 V~
- Industry standard outline
- RoHS compliant
- Soldering pins for PCB mounting
- Height: 17 mm
- Base plate: Copper internally DCB isolated
- Advanced power cycling

IGBT

Symbol	Definition	Conditions	Ratings				
			min.	typ.	max.		
V_{CES}	collector emitter voltage	$T_{VJ} = 25^\circ C$			1200	V	
V_{GES}	max. DC gate voltage				± 20	V	
V_{GEM}	max. transient gate emitter voltage				± 30	V	
I_{C25}	collector current	$T_c = 25^\circ C$			465	A	
I_{C80}		$T_c = 80^\circ C$			325	A	
P_{tot}	total power dissipation	$T_c = 25^\circ C$			1500	W	
$V_{CE(sat)}$	collector emitter saturation voltage	$I_c = 300 A; V_{GE} = 15 V$	$T_{VJ} = 25^\circ C$	1.8	2.1	V	
			$T_{VJ} = 125^\circ C$	2.15		V	
$V_{GE(th)}$	gate emitter threshold voltage	$I_c = 12 mA; V_{GE} = V_{CE}$	$T_{VJ} = 25^\circ C$	5.4	5.9	6.5	V
I_{CES}	collector emitter leakage current	$V_{CE} = V_{CES}; V_{GE} = 0 V$	$T_{VJ} = 25^\circ C$		0.3	mA	
			$T_{VJ} = 125^\circ C$	0.3		mA	
I_{GES}	gate emitter leakage current	$V_{GE} = \pm 20 V$			1.5	μA	
$Q_{G(on)}$	total gate charge	$V_{CE} = 600 V; V_{GE} = 15 V; I_c = 300 A$		885		nC	
$t_{d(on)}$	turn-on delay time	inductive load $V_{CE} = 600 V; I_c = 300 A$ $V_{GE} = \pm 15 V; R_G = 2.2 \Omega$		110		ns	
t_r	current rise time			68		ns	
$t_{d(off)}$	turn-off delay time			290		ns	
t_f	current fall time			345		ns	
E_{on}	turn-on energy per pulse			20		mJ	
E_{off}	turn-off energy per pulse			42		mJ	
RBSOA	reverse bias safe operating area	$V_{GE} = \pm 15 V; R_G = 2.2 \Omega$	$T_{VJ} = 125^\circ C$				
I_{CM}		$V_{CEmax} = 1200 V$			650	A	
SCSOA	short circuit safe operating area	$V_{CEmax} = 1200 V$					
t_{sc}	short circuit duration	$V_{CE} = 900 V; V_{GE} = \pm 15 V$	$T_{VJ} = 125^\circ C$		10	μs	
I_{sc}	short circuit current	$R_G = 2.2 \Omega$; non-repetitive		tbd		A	
R_{thJC}	thermal resistance junction to case				0.085	K/W	
R_{thCH}	thermal resistance case to heatsink				0.04	K/W	

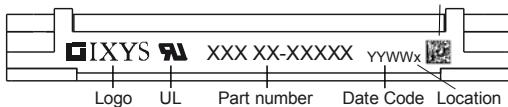
Diode

V_{RRM}	max. repetitive reverse voltage	$T_{VJ} = 25^\circ C$		1200	V
I_{F25}	forward current	$T_c = 25^\circ C$		265	A
I_{F80}		$T_c = 80^\circ C$		185	A
V_F	forward voltage	$I_F = 300 A$	$T_{VJ} = 25^\circ C$	2.20	V
			$T_{VJ} = 125^\circ C$	1.90	V
I_R	reverse current	$V_R = V_{RRM}$	$T_{VJ} = 25^\circ C$	*	μA
	* not applicable, see I_{CES} value above		$T_{VJ} = 125^\circ C$	*	μA
Q_{rr}	reverse recovery charge	$V_R = 600 V$ $-di_F/dt = 4500 A/\mu s$ $I_F = 300 A; V_{GE} = 0 V$		38	μC
I_{RM}	max. reverse recovery current			300	A
t_{rr}	reverse recovery time			350	ns
E_{rec}	reverse recovery energy			15	mJ
R_{thJC}	thermal resistance junction to case			0.145	K/W
R_{thCH}	thermal resistance case to heatsink			0.05	K/W

tentative

Package SimBus F			Ratings		
Symbol	Definition	Conditions	min.	typ.	max.
					Unit
I_{RMS}	RMS current	per terminal			A
T_{stg}	storage temperature		-40		125 °C
T_{VJ}	virtual junction temperature		-40		150 °C
Weight				350	g
M_D	mounting torque		3		6 Nm
M_T	terminal torque		3		6 Nm
$d_{Spp/App}$	creepage distance on surface striking distance through air	terminal to terminal	12.7		mm
$d_{Spb/Apb}$		terminal to backside	10.0		mm
V_{ISOL}	isolation voltage	t = 1 second t = 1 minute 50/60 Hz, RMS; $I_{ISOL} \leq 1$ mA	3000 2500		V V
$R_{pin-chip}$	resistance pin to chip	$V = V_{CEsat} + 2 \cdot R \cdot I_c$ resp. $V = V_F + 2 \cdot R \cdot I_F$		0.65	mΩ

2D Data Matrix

**Part number**

M = Module
 I = IGBT
 X = XPT IGBT
 A = Gen 1 / std
 300 = Current Rating [A]
 PF = Phase leg + free wheeling Diodes
 1200 = Reverse Voltage [V]
 T = Thermistor \ Temperature sensor
 SF = SimBus F

Ordering	Part Number	Marking on Product	Delivery Mode	Quantity	Code No.
Standard	MIXA300PF1200TSF	MIXA300PF1200TSF	Box	3	512264

Temperature Sensor NTC

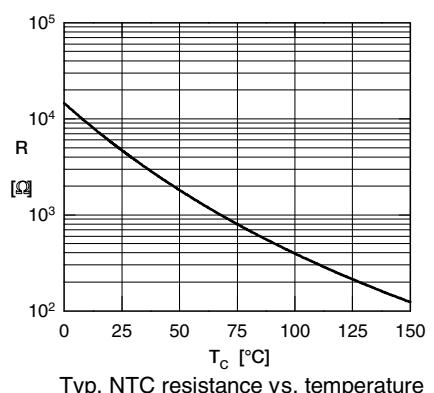
Symbol	Definition	Conditions	min.	typ.	max.	Unit
R_{25}	resistance	$T_{VJ} = 25^\circ C$	4.75	5	5.25	kΩ
$B_{25/50}$	temperature coefficient			3375		K

Equivalent Circuits for Simulation

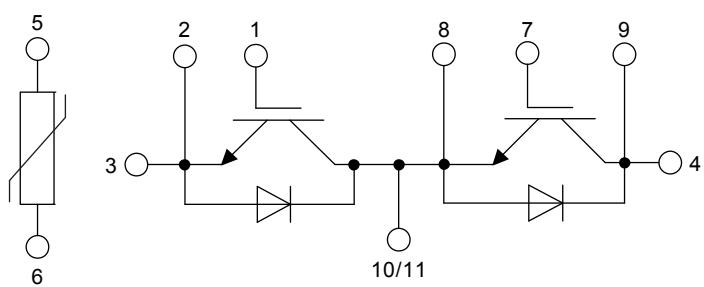
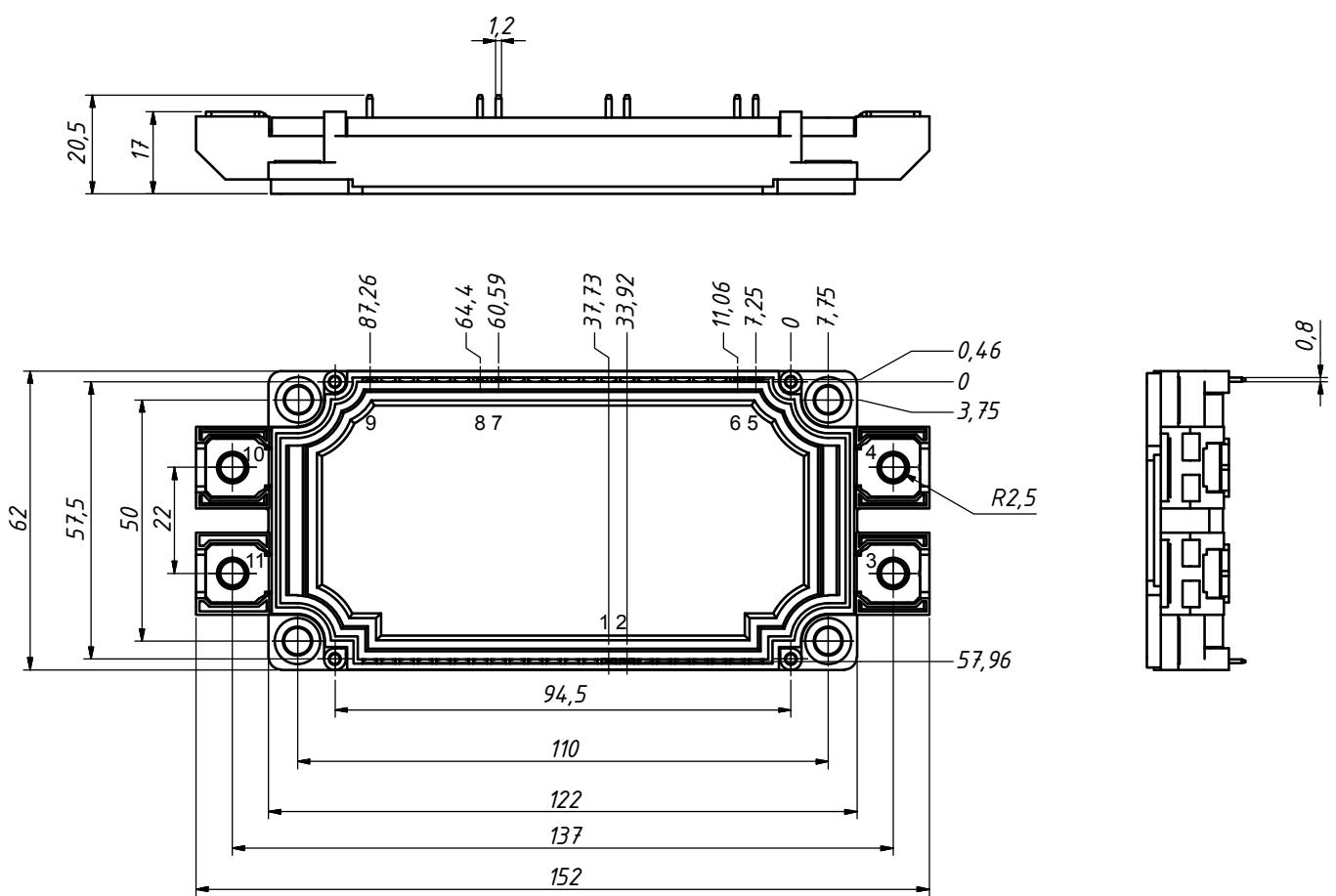
* on die level

 $T_{VJ} = 150^\circ C$

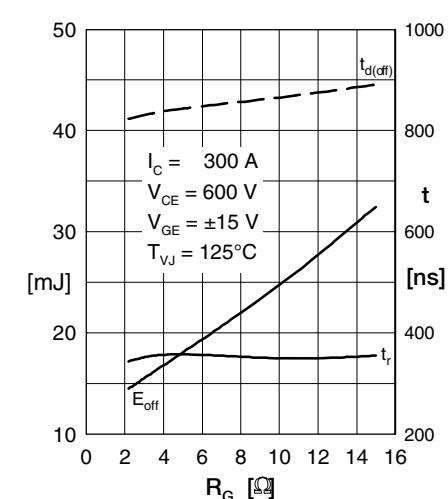
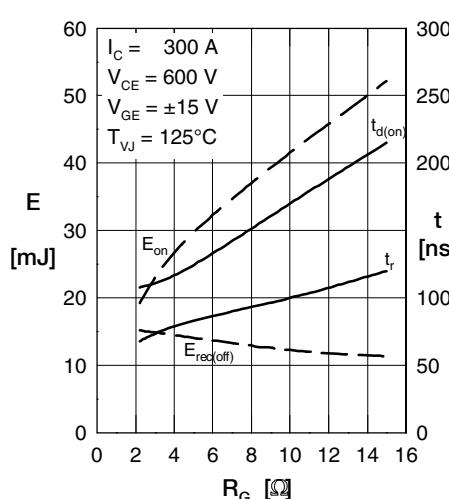
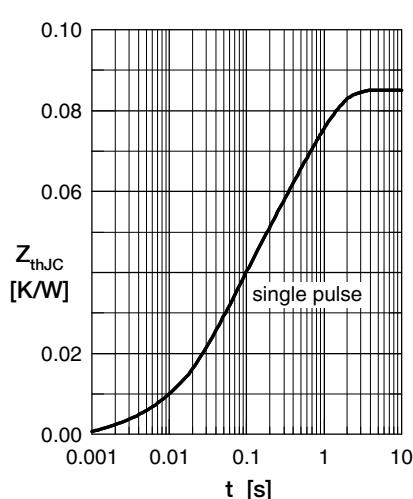
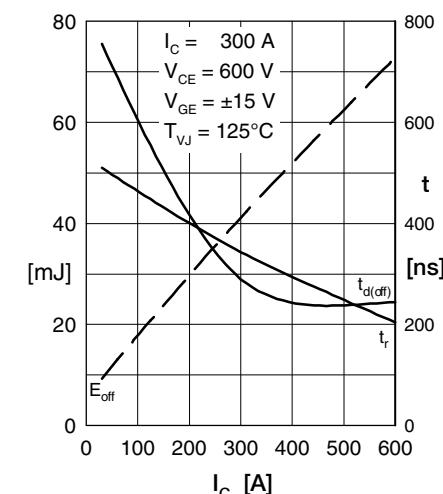
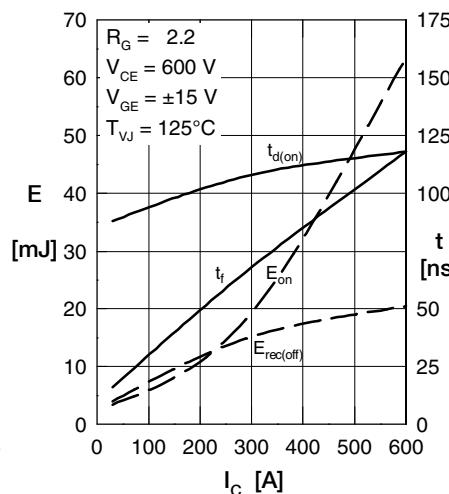
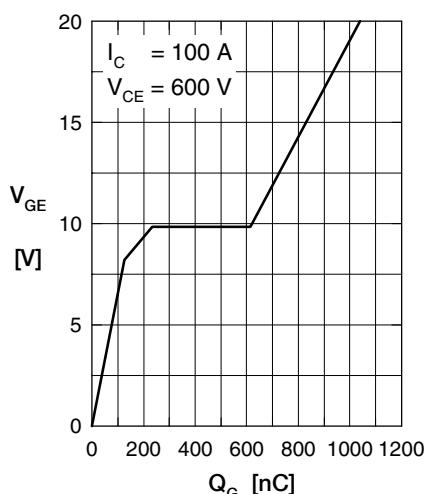
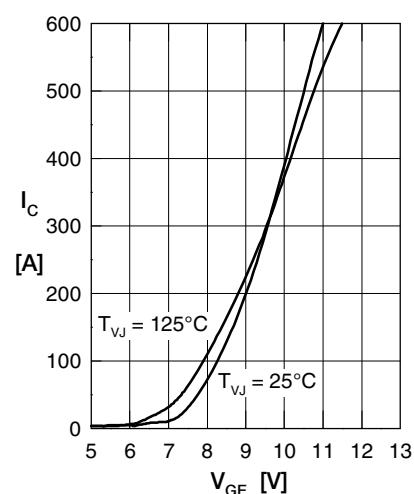
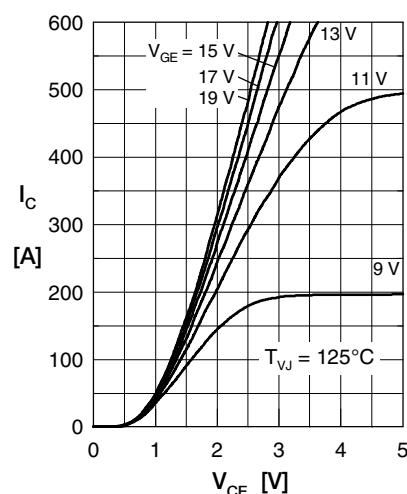
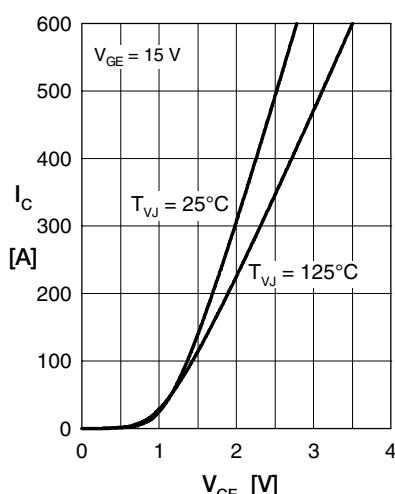
		IGBT	Diode
V_0	threshold voltage	1.1	1.25 V
$R_{0\max}$	slope resistance *	4.6	8.5 mΩ



Outlines SimBus F



IGBT



Diode

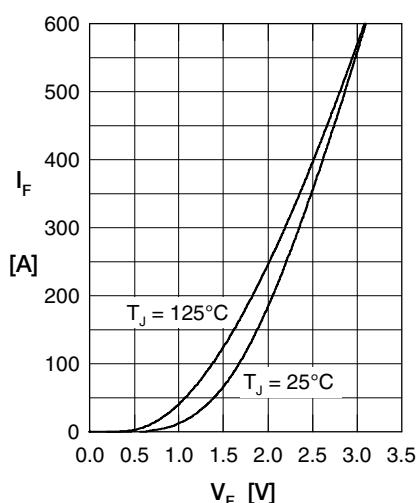
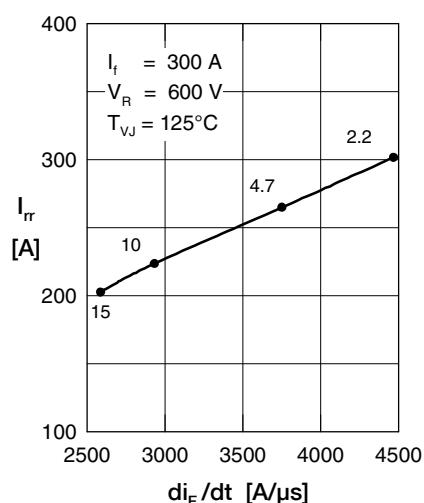
Fig. 1 Typ. Forward current versus V_F 

Fig. 2 Typ. reverse recovery characteristics

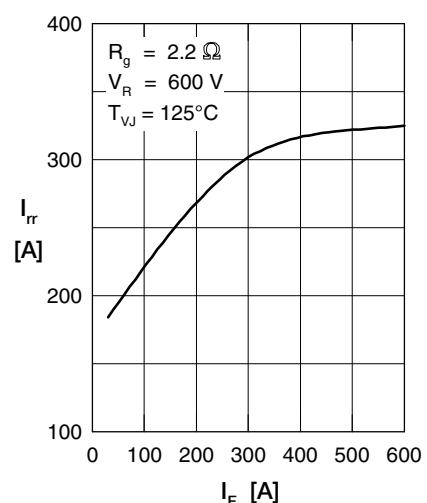


Fig. 3 Typ. reverse recovery characteristics

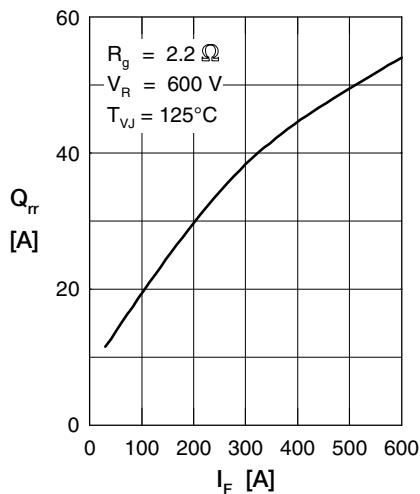


Fig. 4 Typ. reverse recovery characteristics

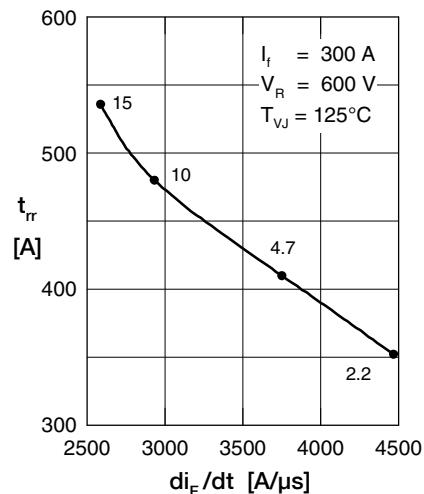
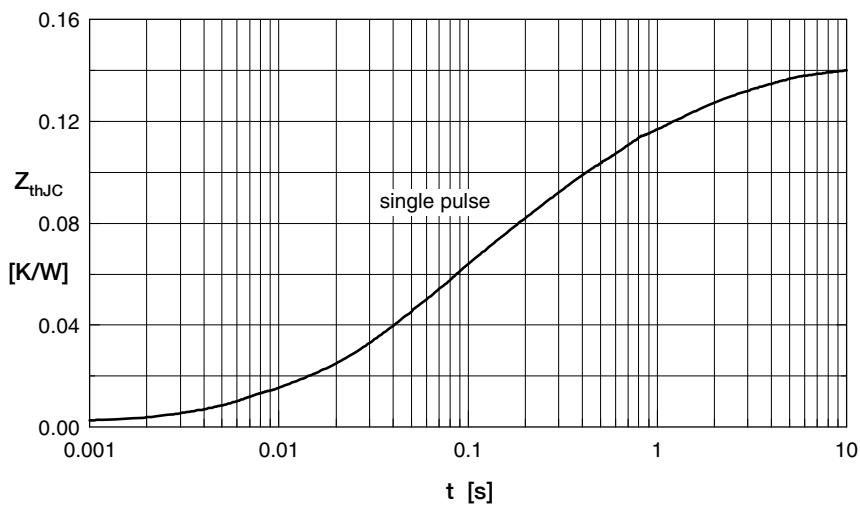
Fig. 5 Typ. recovery time t_{rr} versus $-di_F/dt$ 

Fig. 7 Typ. transient thermal impedance junction to case